

Reliability evaluation of isolated buck-boost DC-DC series resonant converter

Bakeer, Abualkasim Ahmed Ali; Chub, Andrii; Shen, Yanfeng IEEE open journal of power electronics 2022 / p. 131-141

<https://doi.org/10.1109/OJPEL.2022.3157200> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)